

0.5µm Probe Lap® Lapping Film

PCC-PA-0001

PRODUCT ANNOUNCEMENT FOR NEW 0.5µM PROBE LAP® LAPPING FILM

Since 1999, International Test Solutions has been designing and manufacturing cleaning materials for advanced probe cards, test sockets, and equipment chucks for wafer sort/probe, final test/burn in, and semiconductor fabrication operations. These cleaning materials enable device manufacturers and foundries to maximize uptime and throughput for substantial test cost savings.

As a part of ITS's commitment to improve quality and develop materials with superior performance across an extended temperature range, ITS is releasing a high performance 0.5µm lapping film which will replace our current 0.5 micron Probe Lap. This new 0.5µm Probe Lap material has more uniform performance across an extended temperature range while maintaining low wear characteristics.

Some of the advantages of the new 0.5µm Probe Lap lapping film are as follows:

- Improved thermal stability from -50C to 200C
- Low wear rates as compared to traditional 0.5µm lapping films
- Improved surface uniformity for improved surface texturing
- Improved durability for substantially longer life time
- Lower overall cost

The new 0.5µm Probe Lap will replace the current 0.5µm Probe Lap and is available immediately.

If you have any questions please contact your regional sales office or ITS directly at 1595 Meadow Wood Lane, Reno, NV 89502 or by telephone at +1 775-284-9220.

Probe Lap® is registered trademark of International Test Solutions.

For more information, please contact:

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